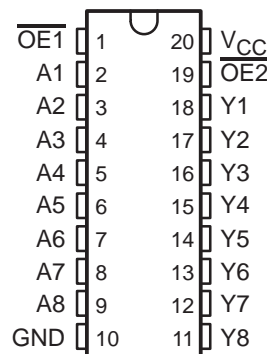


# SN54LVTH540, SN74LVTH540 3.3-V ABT OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

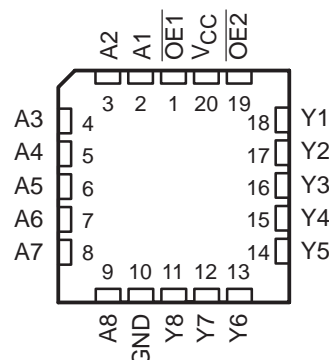
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- State-of-the-Art Advanced BiCMOS Technology (ABT) Design for 3.3-V Operation and Low Static-Power Dissipation
- $I_{off}$  and Power-Up 3-State Support Hot Insertion
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Support Mixed-Mode Signal Operation (5-V Input and Output Voltages With 3.3-V  $V_{CC}$ )
- Support Unregulated Battery Operation Down to 2.7 V
- Typical  $V_{OLP}$  (Output Ground Bounce)  $< 0.8$  V at  $V_{CC} = 3.3$  V,  $T_A = 25^\circ\text{C}$
- Latch-Up Performance Exceeds 500 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model ( $C = 200$  pF,  $R = 0$ )
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Ceramic Flat (W) Package, and Ceramic (J) DIPs

SN54LVTH540 . . . J OR W PACKAGE  
SN74LVTH540 . . . DB, DW, OR PW PACKAGE  
(TOP VIEW)



SN54LVTH540 . . . FK PACKAGE  
(TOP VIEW)



## description

These octal buffers/drivers are designed specifically for low-voltage (3.3-V)  $V_{CC}$  operation, but with the capability to provide a TTL interface to a 5-V system environment.

The 'LVTH540 devices are ideal for driving bus lines or buffer memory address registers. These devices feature inputs and outputs on opposite sides of the package that facilitate printed circuit board layout.

The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable ( $\overline{OE1}$  or  $\overline{OE2}$ ) input is high, all outputs are in the high-impedance state.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

When  $V_{CC}$  is between 0 and 1.5 V, the devices are in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 1.5 V,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

These devices are fully specified for hot-insertion applications using  $I_{off}$  and power-up 3-state. The  $I_{off}$  circuitry disables the outputs, preventing damaging current backflow through the devices when they are powered down. The power-up 3-state circuitry places the outputs in the high-impedance state during power up and power down, which prevents driver conflict.



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**TEXAS  
INSTRUMENTS**

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SN54LVTH540, SN74LVTH540  
3.3-V ABT OCTAL BUFFERS/DRIVERS  
WITH 3-STATE OUTPUTS

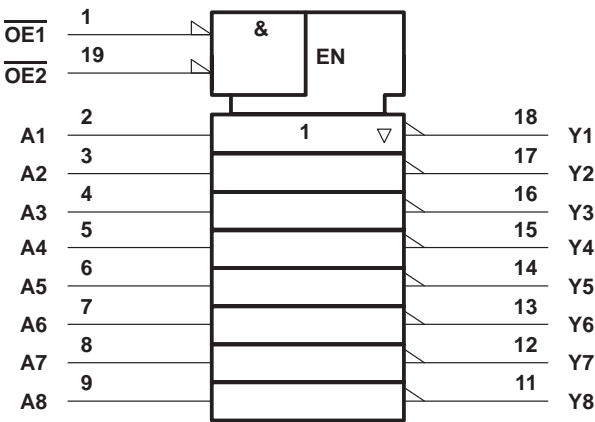
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description (continued)

The SN54LVTH540 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ .  
The SN74LVTH540 is characterized for operation from  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ .

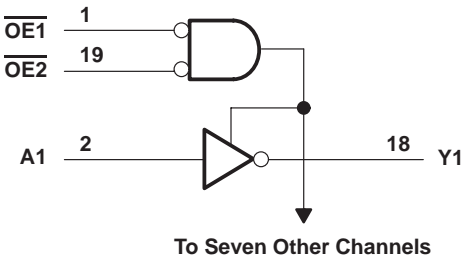
FUNCTION TABLE			
INPUTS			OUTPUT Y
$\overline{\text{OE1}}$	$\overline{\text{OE2}}$	A	
L	L	L	H
L	L	H	L
H	X	X	Z
X	H	X	Z

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



# SN54LVTH540, SN74LVTH540

## 3.3-V ABT OCTAL BUFFERS/DRIVERS

### WITH 3-STATE OUTPUTS

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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, $V_{CC}$	–0.5 V to 4.6 V
Input voltage range, $V_I$ (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high-impedance or power-off state, $V_O$ (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high state, $V_O$ (see Note 1)	–0.5 V to $V_{CC} + 0.5$ V
Current into any output in the low state, $I_O$ : SN54LVTH540	96 mA
SN74LVTH540	128 mA
Current into any output in the high state, $I_O$ (see Note 2): SN54LVTH540	48 mA
SN74LVTH540	64 mA
Input clamp current, $I_{IK}$ ( $V_I < 0$ )	–50 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ )	–50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 3): DB package	115°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, $T_{stg}$	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.  
2. This current flows only when the output is in the high state and  $V_O > V_{CC}$ .  
3. The package thermal impedance is calculated in accordance with JESD 51.

#### recommended operating conditions (see Note 4)

		SN54LVTH540		SN74LVTH540		UNIT
		MIN	MAX	MIN	MAX	
$V_{CC}$	Supply voltage	2.7	3.6	2.7	3.6	V
$V_{IH}$	High-level input voltage	2		2		V
$V_{IL}$	Low-level input voltage		0.8		0.8	V
$V_I$	Input voltage		5.5		5.5	V
$I_{OH}$	High-level output current		–24		–32	mA
$I_{OL}$	Low-level output current		48		64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate		10		10	ns/V
$\Delta t/\Delta V_{CC}$	Power-up ramp rate	200		200		μs/V
$T_A$	Operating free-air temperature	–55	125	–40	85	°C

NOTE 4: All unused control inputs of the device must be held at  $V_{CC}$  or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

# SN54LVTH540, SN74LVTH540

## 3.3-V ABT OCTAL BUFFERS/DRIVERS

### WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54LVTH540			SN74LVTH540			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
$V_{IK}$	$V_{CC} = 2.7\text{ V}$ ,	$I_I = -18\text{ mA}$			-1.2			-1.2	V
$V_{OH}$	$V_{CC} = 2.7\text{ V to }3.6\text{ V}$ ,	$I_{OH} = -100\text{ }\mu\text{A}$	$V_{CC}-0.2$			$V_{CC}-0.2$			V
	$V_{CC} = 2.7\text{ V}$ ,	$I_{OH} = -8\text{ mA}$	2.4			2.4			
	$V_{CC} = 3\text{ V}$	$I_{OH} = -24\text{ mA}$	2						
		$I_{OH} = -32\text{ mA}$				2			
$V_{OL}$	$V_{CC} = 2.7\text{ V}$	$I_{OL} = 100\text{ }\mu\text{A}$			0.2			0.2	V
		$I_{OL} = 24\text{ mA}$			0.5			0.5	
	$V_{CC} = 3\text{ V}$	$I_{OL} = 16\text{ mA}$			0.4			0.4	
		$I_{OL} = 32\text{ mA}$			0.5			0.5	
		$I_{OL} = 48\text{ mA}$			0.55				
		$I_{OL} = 64\text{ mA}$						0.55	
$I_I$		$V_{CC} = 0\text{ or }3.6\text{ V}$ ,			10			10	$\mu\text{A}$
	Control inputs	$V_{CC} = 3.6\text{ V}$ ,			$\pm 1$			$\pm 1$	
	Data inputs	$V_I = V_{CC}$			1			1	
		$V_I = 0$			-5			-5	
$I_{off}$		$V_{CC} = 0$ ,						$\pm 100$	$\mu\text{A}$
$I_{I(hold)}$	Data inputs	$V_{CC} = 3\text{ V}$			75			75	$\mu\text{A}$
		$V_I = 0.8\text{ V}$			-75			-75	
		$V_I = 2\text{ V}$							
		$V_{CC} = 3.6\text{ V}^\ddagger$ ,						$\pm 500$	
		$V_I = 0\text{ to }3.6\text{ V}$							
$I_{OZH}$		$V_{CC} = 3.6\text{ V}$ ,			5			5	$\mu\text{A}$
		$V_O = 3\text{ V}$							
$I_{OZL}$		$V_{CC} = 3.6\text{ V}$ ,			-5			-5	$\mu\text{A}$
		$V_O = 0.5\text{ V}$							
$I_{OZPU}$		$V_{CC} = 0\text{ to }1.5\text{ V}$ , $V_O = 0.5\text{ V to }3\text{ V}$ , $\overline{OE} = \text{don't care}$			$\pm 100^*$			$\pm 100$	$\mu\text{A}$
$I_{OZPD}$		$V_{CC} = 1.5\text{ V to }0$ , $V_O = 0.5\text{ V to }3\text{ V}$ , $\overline{OE} = \text{don't care}$			$\pm 100^*$			$\pm 100$	$\mu\text{A}$
$I_{CC}$	$V_{CC} = 3.6\text{ V}$ , $I_O = 0$ , $V_I = V_{CC}\text{ or GND}$	Outputs high			0.19			0.19	mA
		Outputs low			5			5	
		Outputs disabled			0.19			0.19	
$\Delta I_{CC}^\S$		$V_{CC} = 3\text{ V to }3.6\text{ V}$ , One input at $V_{CC} - 0.6\text{ V}$ , Other inputs at $V_{CC}\text{ or GND}$			0.2			0.2	mA
$C_i$		$V_I = 3\text{ V or }0$			3			3	pF
$C_o$		$V_O = 3\text{ V or }0$			7			7	pF

\* On products compliant to MIL-PRF-38535, this parameter is not production tested.

† All typical values are at  $V_{CC} = 3.3\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

‡ This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than  $V_{CC}$  or GND.

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# SN54LVTH540, SN74LVTH540 3.3-V ABT OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature,  $C_L = 50$  pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	SN54LVTH540				SN74LVTH540				UNIT	
			V <sub>CC</sub> = 3.3 V ± 0.3 V		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V			V <sub>CC</sub> = 2.7 V		
			MIN	MAX	MIN	MAX	MIN	TYP†	MAX	MIN		MAX
t <sub>PLH</sub>	A	Y	1	3.9		4.7	1.1	2.4	3.8		4.6	ns
t <sub>PHL</sub>			1	3.9		4.7	1.1	2.7	3.8		4.6	
t <sub>PZH</sub>	OE1 or OE2	Y	1.4	5.3		6.3	1.5	3.4	5.2		6.2	ns
t <sub>PZL</sub>			1.4	5.5		6.1	1.5	3.7	5.3		5.9	
t <sub>PHZ</sub>	OE1 or OE2	Y	1.4	5.9		6.2	1.5	3.9	5.6		5.9	ns
t <sub>PLZ</sub>			1.4	5.5		5.8	1.5	3.5	5		5.3	

† All typical values are at  $V_{CC} = 3.3\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

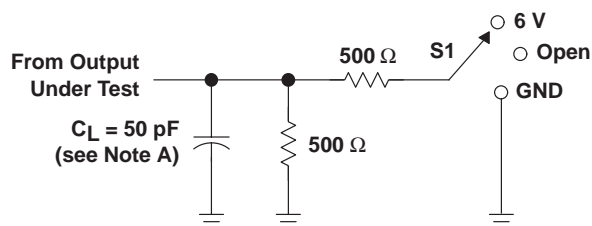
# SN54LVTH540, SN74LVTH540

## 3.3-V ABT OCTAL BUFFERS/DRIVERS

### WITH 3-STATE OUTPUTS

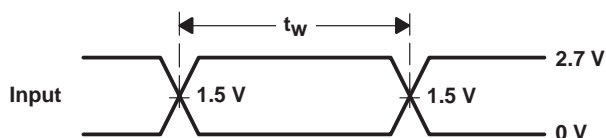
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#### PARAMETER MEASUREMENT INFORMATION

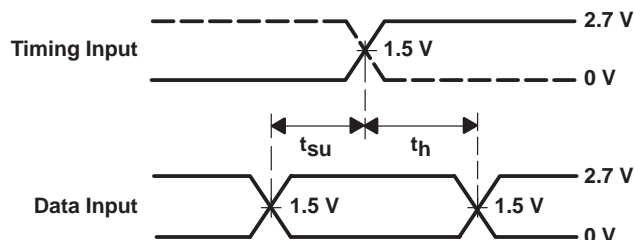


LOAD CIRCUIT

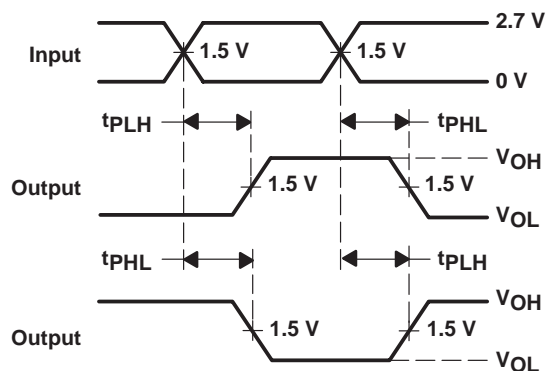
TEST	S1
$t_{PHL}/t_{PLH}$	Open
$t_{PLZ}/t_{PZL}$	6 V
$t_{PHZ}/t_{PZH}$	GND



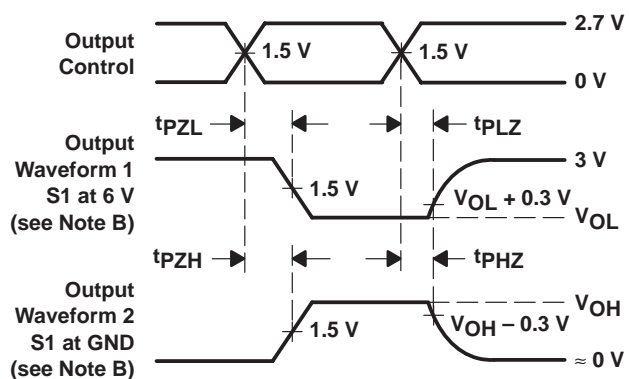
VOLTAGE WAVEFORMS  
PULSE DURATION



VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS  
PROPAGATION DELAY TIMES  
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS  
ENABLE AND DISABLE TIMES  
LOW- AND HIGH-LEVEL ENABLING

- NOTES:
- $C_L$  includes probe and jig capacitance.
  - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_r \leq 2.5 \text{ ns}$ ,  $t_f \leq 2.5 \text{ ns}$ .
  - The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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